

Search Notes**Application/Control No.**

10/708,489

Examiner

Y. J. Han

Applicant(s)/Patent under Reexamination

CHANG ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
323	312		
	313		
	314		
	274		
	275		
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	277		
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	281		
327	530		
	534		
	535	12/05	gA

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner